


<b>Search Notes</b>  	<b>Application/Control No.</b>  10595523	<b>Applicant(s)/Patent Under Reexamination</b>  NAKAYAMA ET AL.
	<b>Examiner</b>  JAE LEE	<b>Art Unit</b>  2823

SEARCHED			
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SEARCH NOTES		
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EAST search: see attached search histories	07/10/2008	JML
continued EAST search	07/15/2008	JML
continued EAST search	06/02/2009	JML

INTERFERENCE SEARCH			
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